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- Package Options Include Plastic "Small Outline" Packages, Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

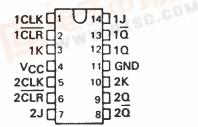
description

The '73, and 'H73, contain two independent J-K flip-flops with individual J-K, clock, and direct clear inputs. The '73, and 'H73, are positive pulse-triggered flip-flops. J-K input is loaded into the master while the clock is high and transferred to the slave on the high-to-low transition. For these devices the J and K inputs must be stable while the clock is high.

The 'LS73A contains two independent negative-edge-triggered flip-flops. The J and K inputs must be stable one setup time prior to the high-to-low clock transition for predictable operation. When the clear is low, it overrides the clock and data inputs forcing the Ω output low and the $\overline{\Omega}$ output high.

The SN5473, SN54H73, and the SN54LS73A are characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 $^{\circ}\text{C}$. The SN7473, and the SN74LS73A are characterized for operation from 0 $^{\circ}\text{C}$ to 70 $^{\circ}\text{C}$.

SN5473, SN54LS73A . . . J OR W PACKAGE SN7473 . . . N PACKAGE SN74LS73A . . . D OR N PACKAGE (TOP VIEW)



73
FUNCTION TABLE

	INPUT	OUT	PUTS		
CLR	CLK	J	K	Q	ā
L	×	X	X	L	Н
Н	J	L	L	00	\bar{a}_0
Н	九	Н	L	H	L
н	ъ.	L	Н	L	Н
Н	T	Н	Н	TOG	GLE

'LS73A
FUNCTION TABLE

	INPUT	OUTP	UTS		
CLR	CLK	J	K	Q	₫
L	×	X	×	L	Н
н	1	L	L	00	\overline{a}_0
н	1	Н	L	н	L
Н	Į.	L	H	L	Н
н	1	Н	Н	TOG	GLE
Н	Н	Х	×	αo	\bar{a}_0

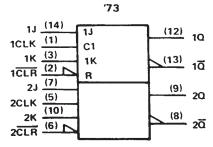
FOR CHIP CARRIER INFORMATION.
CONTACT THE FACTORY

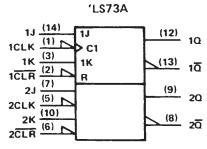


SN5473, SN54LS73A, SN7473, SN74LS73A DUAL J-K FLIP-FLOPS WITH CLEAR

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logic symbols†



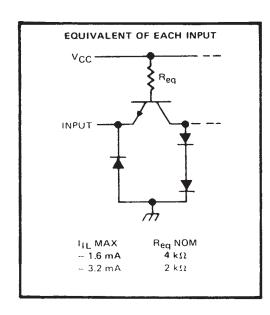


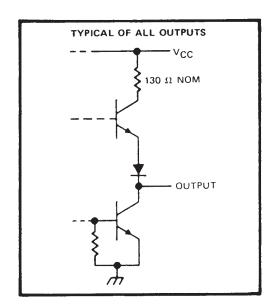
[†]These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

'73

'LS73

schematics of inputs and outputs





INPUT

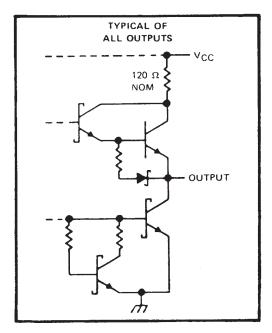
INPUT

Req NOM

- 0.4 mA

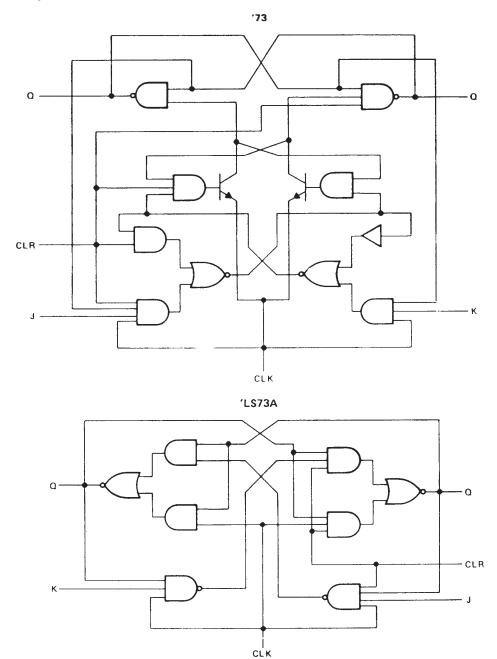
- 0.8 mA

8.25 kΩ





logic diagrams (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (See Note 1)	/ V
Input voltage: '73	5.5 V
LS73A	7 V
Operating free-air temperature range: SN54'	55°C to 125°C
SN74'	0° C to 70°C
Storage temperature range	65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



SN5473, SN54LS73A, SN7473, SN74LS73A DUAL J-K FLIP-FLOPS WITH CLEAR

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recommended operating conditions

				SN547	SN5473		SN747	3	IMIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
VIH	High-level input voltage		2			2			٧
VIL	Low-level input voltage				0.8			0.8	٧
ЮН	High-level output current				- 0.4			- 0.4	mA
loL	Low-level output current				16			16	mA
		CLK high	20			20			
tw	Pulse duration	CLK low	47			47			ns
		CLR low	25			25			
t _{su}	Input setup time before CLK t		0			0			ns
th	Input hold time data after CLK↓		0			0			ns
TA	Operating free-air temperature		- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

200		TEST CONDITIONS [†]				SN5473			SN7473		UNIT
PAI	RAMETER	111	EST CONDITION	181	MIN	TYP‡	MAX	MIN	TYP\$	MAX	UNIT
VIK		V _{CC} = MIN,	I _I = - 12 mA				- 1.5			- 1.5	٧
Vон		V _{CC} = MIN, I _{OH} = - 0.4 mA	V _{IH} = 2 V,	V _{IL} = 0.8 V,	2.4	3.4		2.4	3.4		٧
VOL		V _{CC} = MIN, I _{OL} = 16 mA	V _{IH} = 2 V,	V _{IL} = 0.8 V,		0.2	0.4		0.2	0.4	٧
11		V _{CC} = MAX,	V _I = 5.5 V				1			1	mA
ЧН	J or K	V _{CC} = MAX,	V ₁ = 2.4 V				40 80			40 80	μА
	Jor K						- 1.6			- 1.6	
ItL	CLR	V _{CC} = MAX,	V ₁ = 0.4 V				- 3,2			- 3.2	mA
	CLK		·				- 3.2			- 3.2	}
los§		V _{CC} = MAX			- 20		57	- 18		- 57	mA
Icc1		V _{CC} = MAX,	See Note 2			10	20		10	20	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, VCC = 5 V, TA = 25°C (see note 3)

PARAMETER#	FROM (INPUT)	TO (OUTPUT)	TEST COND	TEST CONDITIONS				UNIT
f _{max}					15	20		MHz
^t PLH	CLR	₫.				16	25	ns
^t PHL	CLN	Q	$R_L = 400 \Omega$,	C _L = 15 pF		25	40	กร
^t PLH	CLK	Q or Q				16	25	ns
^t PHL	CLK	2012			25	40	กร	

[#]f_{max} = maximum clock frequency: tp_{LH} = propagation delay time, low-to-high-level output; tp_{HL} = propagation delay time, high-to-low-level output.

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



 $^{^{\}ddagger}$ All typical values are at VCC = 5 V, TA = 25 °C.

[§] Not more than one output should be shorted at a time.

Average per flip-flop.

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recommended operating conditions

			SI	SN54LS73A			SN74LS73A		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
ViH	High-level input voltage		2			2			٧
VIL	Low-level input voltage				0.7			0.8	V
Іон	High-level output current				- 0.4			- 0.4	mA
loL	Low-level output current			4			8	mA	
fclock	Clock frequency		0		30	0		30	MHz
	Pulse duration	CLK high	20			20			
t _w	ruise duration	CLR low	25			20			ns
	Set up time before CLK1	data high or low	20			20			
t _{su}	Set up time-before CLK4 CLR inactive		20			20			ns
th	Hold time-data after CLK↓		0			0			ns
TA	Operating free-air temperature		- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		_	TOT COMPLETION	et	SI	N54LS7	3A	SI	UNIT								
77	HAMEIEH		EST CONDITION	5'	MIN	TYP#	MAX	MIN	TYP‡	MAX	UNII						
VIK		V _{CC} = MIN,	$t_1 = -18 \text{ mA}$				- 1.5			- 1.5	V						
Vон		V _{CC} = MIN, I _{OH} = - 0.4 mA	V _{IH} = 2 V,	V _{IL} = MAX,	2.5	3.4		2.7	3.4		٧						
		V _{CC} = MIN, I _{OL} = 4 mA	VIL = MAX,	V _{IH} = 2 V,		0.25	0.4		0.25	0.4	V						
VOL		V _{CC} = MIN, I _{OL} = 8 mA	VIL = MAX,	V _{1H} = 2 V,					0.35	0.5] `						
	J or K						0.1			0.1							
H	CLR	V _{CC} = MAX,	V1 = 7 V	V ₁ = 7 V			0.3			0.3	mA						
	CLK	1	-				0.4			0.4	<u> </u>						
	J or K						20			20							
ЧН	CLR	V _{CC} = MAX,	V ₁ = 2.7 V	V _I = 2.7 V	V ₁ = 2.7 V	V ₁ = 2.7 V	V ₁ = 2.7 V	V _I = 2.7 V	V _I = 2.7 V				60			60	μА
	CLK	1					80			80]						
	J or K						0.4			- 0,4							
11L	CLR or CLK	V _{CC} = MAX,	V ₁ = 0.4 V				- 0.8			- 0.8	mA						
1 _{OS} \$		V _{CC} = MAX,	See Note 4		- 20		- 100	- 20		- 100	mA						
ICC (T	otal)	V _{CC} = MAX,	See Note 2			4	6		4	6	mA						

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	TEST CONDITIONS				UNIT
fmax					30	45		MHz
^t PLH	<u> </u>	Q or $\overline{\overline{Q}}$	$R_L = 2 k\Omega$,	CL = 15 pF		15	20	ns
[†] PHL	CLR or CLK	u or u				15	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{C}$.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and Q outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the 54 family and the 74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

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